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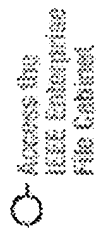
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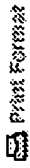
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1 Retrieval of paintings using effects induced by color features

Corridoni, J.M.; del Bimbo, A.; Pala, P.;
Content-Based Access of Image and Video Database, 1998. Proceedings., 1998
IEEE International Workshop on , 3 Jan. 1998
Pages:2 - 11

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